

#### **Description**

The AP3P10S uses advanced trench technology to provide excellent  $R_{DS(ON)}$ , low gate charge and operation with gate voltages as low as 4.5V. This device is suitable for use as a

Battery protection or in other Switching application.

#### **General Features**

 $V_{DS} = -100V I_D = -3A$ 

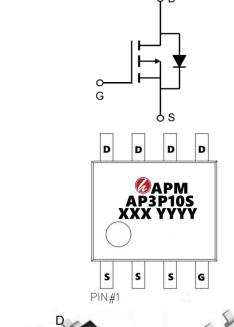
 $R_{DS(ON)} < 600 m\Omega$  @  $V_{GS}=10 V$  (Type: 450 m $\Omega$ )

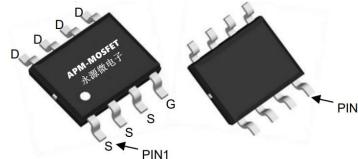
#### **Application**

Battery protection

Load switch

Uninterruptible power supply





**Package Marking and Ordering Information** 

Product ID	Pack	Marking	Qty(PCS)
AP3P10S	SOP-8	AP3P10S XXX YYYY	3000

#### Absolute Maximum Ratings (T<sub>C</sub>=25°Cunless otherwise noted)

Symbol	Parameter	Rating	Units	
Vos	Drain-Source Voltage	-100	V	
Vgs	Gate-Source Voltage	±20	V	
I <sub>D</sub> @T <sub>A</sub> =25°C	Continuous Drain Current, V <sub>GS</sub> @ -10V <sup>1</sup>	-3	Α	
I <sub>D</sub> @T <sub>A</sub> =70°C	Continuous Drain Current, V <sub>GS</sub> @ -10V <sup>1</sup>	-1.7	Α	
Іом	Pulsed Drain Current <sup>2</sup>	-9.8	Α	
P <sub>D</sub> @T <sub>A</sub> =25°C	Total Power Dissipation <sup>3</sup>	1	W	
Тѕтс	Storage Temperature Range	-55 to 150	°C	
TJ	Operating Junction Temperature Range	-55 to 150	°C	
RθJA	Thermal Resistance Junction-ambient <sup>1</sup> 85		°C/W	
R <sub>θ</sub> JC	Thermal Resistance Junction-Case <sup>1</sup> 80 °C/V		°C/W	

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## Electrical Characteristics (T<sub>A</sub>=25°Cunless otherwise noted)

Symbol	Parameter	Conditions	Min.	Тур.	Max.	Unit
BVDSS	Drain-Source Breakdown Voltage	VGS=0V , ID=-250uA	-100	-111		V
△BVDSS/△TJ	BVDSS Temperature Coefficient	Reference to 25°C , ID=-1mA		-0.0624		V/°C
DDC(ON)	Otatia Basia Carres On Basiatan and	VGS=-10V , ID=-0.8A		450	600	mΩ
RDS(ON)	Static Drain-Source On-Resistance2	VGS=-4.5V , ID=-0.4A		560	700	mΩ
VGS(th)	Gate Threshold Voltage	\\CC-\\DC \ID = 050\	-1.0	-1.5	-2.5	V
△VGS(th)	VGS(th) Temperature Coefficient	VGS=VDS , ID =-250uA		4.5		mV/°C
IDSS	Drain-Source Leakage Current	VDS=-80V , VGS=0V ,TJ=25°C	-		10	uA
1033	Diain-Source Leakage Guirent	VDS=-80V , VGS=0V ,TJ=55°C	I		100	uA
IGSS	Gate-Source Leakage Current	VGS=±20V, VDS=0V	I		±100	nA
gfs	Forward Transconductance	VDS=-5V , ID=-0.8A	I	3		S
Rg	Gate Resistance	VDS=0V , VGS=0V , f=1MHz	I	16	32	Ω
Qg	Total Gate Charge (-4.5V)		1	4.5		nC
Qgs	Gate-Source Charge	VDS=-15V , VGS=-4.5V , ID=-0.5A		1.14		nC
Qgd	Gate-Drain Charge	.5 0.6/1		1.5		nC
Td(on)	Turn-On Delay Time		1	13.6		ns
Tr	Rise Time	VDD=-50V , VGS=-10V ,		6.8		ns
Td(off)	Turn-Off Delay Time	RG=3.3Ω ID=-0.5A		34		ns
Tf	Fall Time			3		ns
Ciss	Input Capacitance			553		pF
Coss	Output Capacitance	VDS=-15V , VGS=0V , f=1MHz		29		pF
Crss	Reverse Transfer Capacitance			20		pF
IS	Continuous Source Current1,4	VG=VD=0V , Force Current	-		-0.9	Α
ISM	Pulsed Source Current2,4				-1.8	Α
VSD	Diode Forward Voltage2	VGS=0V , IS=-1A , TJ=25°C			-1.2	V

#### Note:

- 1. The data tested by surface mounted on a 1 inch2 FR-4 board with 2OZ copper.
- $2_{\times}$  The data tested by pulsed , pulse width  $\leqq$  300us , duty cycle  $\leqq$  2%
- $3 {\,{}^{^{\circ}}}$  The power dissipation is limited by  $150 {\,{}^{\circ}\!{}^{^{\circ}}}$  junction temperature
- 4. The data is theoretically the same as ID and IDM, in real applications, should be limited by total power dissipation.



# **Typical Characteristics**

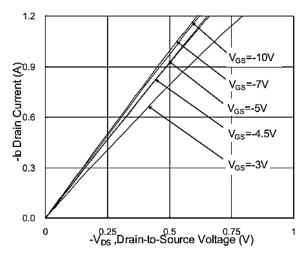


Fig.1 Typical Output Characteristics

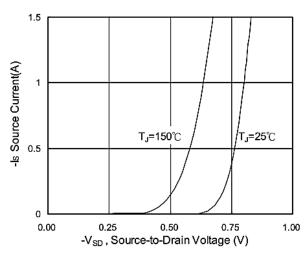


Fig.3 Forward Characteristics Of Reverse

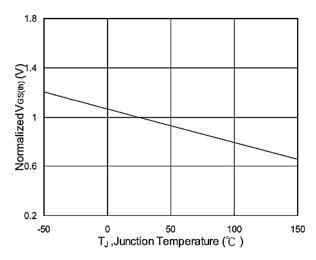


Fig.5 Normalized V<sub>GS(th)</sub> vs. T<sub>J</sub>

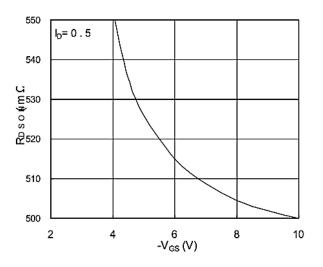


Fig.2 On-Resistance vs. Gate-Source

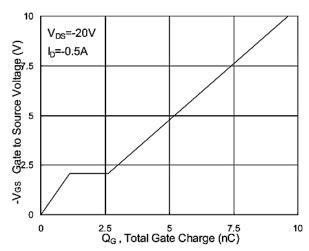


Fig.4 Gate-Charge Characteristics

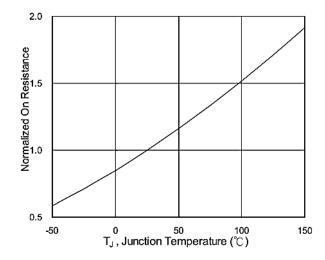
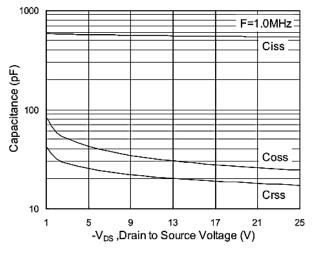


Fig.6 Normalized RDSON vs. TJ







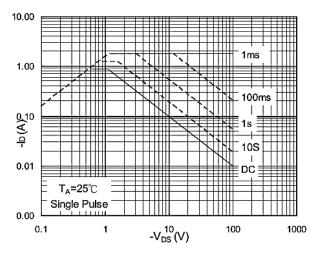


Fig.7 Capacitance

Fig.8 Safe Operating Area

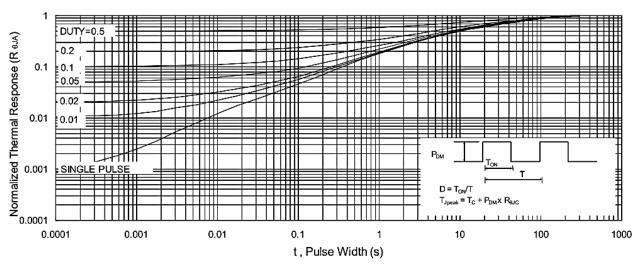
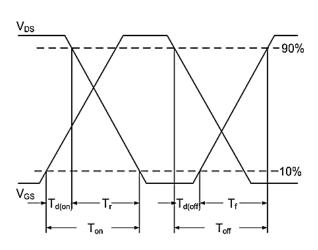


Fig.9 Normalized Maximum Transient Thermal Impedance



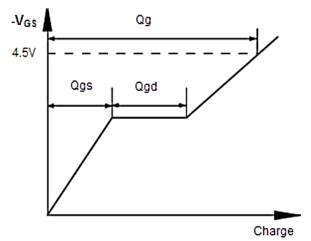


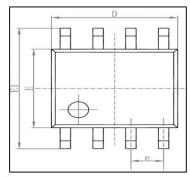
Fig.10 Switching Time Waveform

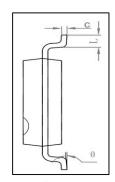
Fig.11 Gate Charge Waveform

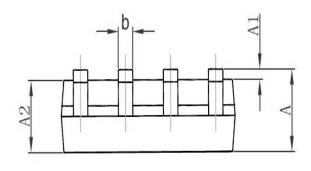
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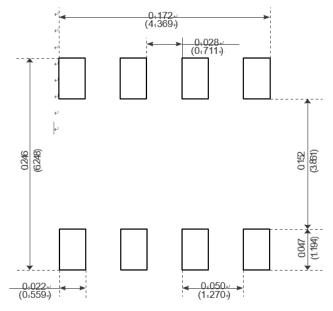
# Package Mechanical Data-SOP-8L







C	Dimensions Ir	n Millimeters	Dimensions	In Inches
Symbol	Min	Max	Min	Max
Α	1. 350	1. 750	0. 053	0.069
A1	0. 100	0. 250	0. 004	0. 010
A2	1. 350	1. 550	0. 053	0. 061
b	0. 330	0. 510	0. 013	0. 020
С	0. 170	0. 250	0.006	0. 010
D	4. 700	5. 100	0. 185	0. 200
E	3.800	4. 000	0. 150	0. 157
E1	5. 800	6. 200	0. 228	0. 244
е	1. 270 (BSC)		0. 050 (BSC)	
L	0. 400	1. 270	0. 016	0.050
θ	0°	8°	0°	8°



Recommended Minimum Pads



# -100V P-Channel Enhancement Mode MOSFET Attention

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Edition	Date	Change
Rve1.0	2020/12/1	Initial release

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